Application/Control No.	Applicant(s)/Patent under Reexamination	
10/618,883	CHEN, CHIH-WEI	
Examiner	Art Unit	
John Chavis	2193	

SEARCHED					
Class	Subclass	Date	Examiner		
717	170	6/7/2006	JC .		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
West (IBM TDB, Derwent, EPO, JPO, PGPUBS, USPAT) anded with word search	6/7/2006	JC.
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